

ABSTRACT OF THE DISCLOSURE

A testing device for testing an electronic device is provided. The testing device includes: a deterministic jitter application unit for applying deterministic jitter to a given input signal without causing an amplitude modulation component and supplying the input signal with the deterministic jitter to the electronic device; a jitter amount controller for controlling the magnitude of the deterministic jitter generated by the deterministic jitter application unit; and a determination unit for determining whether or not the electronic device is defective based on an output signal output from the electronic device in accordance with the input signal.